PATENT 4303-1009

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Harald KRAUS et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed August 8, 2006

Examiner

METHOD FOR SELECTIVE ETCHING

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

August 8, 2006

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

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The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

0/588766 CONCISE EXPLANATION OF THE RELEVANCE REC'D PCT/PTO 08 AUG 2006 (check at least one box) API Rec'd PCT/PTO 08 AUG 2006 DOCUMENTS IN THE ENGLISH LANGUAGE \boxtimes а. The non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy. DOCUMENTS NOT IN THE ENGLISH LANGUAGE b. П A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows: FOREIGN SEARCH REPORT OR ACTION \boxtimes c. An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby requirement satisfying the for а explanation. See MPEP 609(A)(3). OTHER d. The following additional information is provided for the Examiner's consideration. **FEES** This Information Disclosure Statement is being filed concurrently with the filing of a new patent application; therefore, no fee is required. If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned. Respectfully submitted, YOUNG & THOMPSON as

Arlington, VA 22202 Telephone (703) 521-2297 Telefax (703) 685-0573

(703) 979-4709

Enclosures:	\boxtimes	Form PTO-1449(s)					
		Documents					
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IN AN APPLICATION				Applicant: Harald KRAUS et al.							
(Use several sheets if necessary)				Filing Date: August 8, 2006			Group Art Unit:				
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^{*} English language abstract provided for the Examiner's convenience